



Form PTO-1449 (modified)	ATTY. DOCKET NO. MICS:0098 (02-1041)	SERIAL NO. 10/609,089
List of Patents and Publications For Applicant's Information Disclosure Statement	APPLICANT Bill Baggenstoss	
(Use several sheets if necessary)	FILING DATE June 27, 2003	GROUP 2818

**U.S. PATENT DOCUMENTS**

EXAM. INIT.	REF. DES.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
PM	A1	6,418,008	07/09/02	Jost et al.	361	303	03/06/01

**FOREIGN PATENT DOCUMENTS**

EXAM. INIT.	REF. DES.	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION

**OTHER ART**

(Author, Title, Journal, Volume, Pertinent Pages, & Date)		
PM	C1	Murguia, James E., et al., Merging Focused Ion Beam Patterning and Optical Lithography in Device and Circuit Fabrication, Journal of Vacuum Science Technology B, Issue 8 (6), Nov/Dec 1990, pages 1374-1379
PM	C2	Preuninger, J., et al., High Order Lens Aberration Monitor, Microelectronic Engineering 53 (2000), pages 129-132
EXAMINER		DATE CONSIDERED 7/5/05

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

*Information Disclosure Statement--PTO-1449 (Modified)*



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#### U.S. PATENT DOCUMENTS

EXAM. INIT.	REF. DES.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
DM	A1	6,569,574	05/27/03	Bill Baggenstoss	430	5	10/18/99
DM	A2	6,440,612	08/27/02	Bill Baggenstoss	430	5	09/01/99
DM	A3	6,401,236	06/04/02	Bill Baggenstoss et al.	716	19	04/05/99
DM	A4	6,374,396	04/16/02	Bill Baggenstoss et al.	716	19	12/04/98
DM	A5	6,319,644	11/20/01	Pierrat et al.	430	30	02/12/01
DM	A6	6,284,419	09/04/01	Pierrat et al.	430	30	01/24/01
DM	A7	6,120,952	09/19/00	Pierrat et al.	430	30	10/01/98

#### FOREIGN PATENT DOCUMENTS

EXAM. INIT.	REF. DES.	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION

#### OTHER ART

(Author, Title, Journal, Volume, Pertinent Pages, & Date)	
EXAMINER	DATE CONSIDERED
<i>[Signature]</i>	7/6/05

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